
**Vitreous and porcelain enamels —
Low-voltage test for detecting and
locating defects —**

**Part 1:
Swab test for non-profiled surfaces**

*Émaux vitrifiés — Essai à basse tension pour la détection et la
localisation des défauts —*

Partie 1: Essai avec tampon pour les surfaces non profilées

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